

MTM86627

Silicon P-channel MOS FET (FET) Silicon epitaxial planar type (SBD)

For DC-DC converter

For switching circuits

Overview

MTM86627 is the composite MOS FET (P-channel MOS FET and Schottky Barrier Diode) that is highly suitable for DC-DC converter and other switching circuits.

Features

- Built-in schottky barrier diode: $V_R = 15\text{ V}$, $I_F = 700\text{ mA}$
- Low on-resistance: $R_{on} = 80\text{ m}\Omega$ ($V_{GS} = -4.0\text{ V}$)
- Low short-circuit input capacitance (Common source): $C_{iss} = 300\text{ pF}$
- Small package: WSSMini6-F1 (1.6 mm × 1.6 mm × 0.5 mm)
- Low drive Voltage: 1.8 V drive

Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

| | Parameter | Symbol | Rating | Unit |
|---------|--------------------------------|-------------|-------------|------------------|
| FET | Drain-source surrender voltage | V_{DSS} | -20 | V |
| | Gate-source surrender voltage | V_{GSS} | ± 10 | V |
| | Drain current | I_D | -2.0 | A |
| | Peak drain current | I_{DP} | -8.0 | A |
| | Channel temperature | T_{ch} | 150 | $^\circ\text{C}$ |
| | Storage temperature | T_{stg} | -55 to +150 | $^\circ\text{C}$ |
| SBD | Reverse voltage | V_R | 15 | V |
| | Forward current (Average) | $I_{F(AV)}$ | 700 | mA |
| | Junction temperature | T_j | 125 | $^\circ\text{C}$ |
| | Storage temperature | T_{stg} | -55 to +125 | $^\circ\text{C}$ |
| Overall | Total power dissipation * | P_D | 540 | mW |

Note) *: Measuring on ceramic substrate at 40 mm × 38 mm × 0.2 mm
Absolute maximum rating without heat sink for P_D is 150 mW

Package

Code

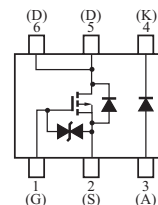
WSSMini6-F1

Pin Name

| | |
|-----------|------------|
| 1: Gate | 4: Cathode |
| 2: Source | 5: Drain |
| 3: Anode | 6: Drain |

Marking Symbol: PK

Internal Connection



■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

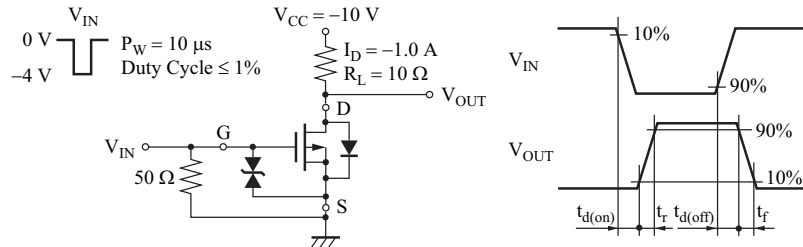
• FET

| Parameter | Symbol | Conditions | Min | Typ | Max | Unit |
|--|--------------|---|------|-------|----------|---------------|
| Drain-source surrender voltage | V_{DSS} | $I_D = -1.0 \text{ mA}, V_{GS} = 0$ | -20 | | | V |
| Drain-source cutoff current | I_{DSS} | $V_{DS} = -20 \text{ V}, V_{GS} = 0$ | | | -1.0 | μA |
| Gate-source cutoff current | I_{GSS} | $V_{GS} = \pm 8 \text{ V}, V_{DS} = 0$ | | | ± 10 | μA |
| Gate threshold voltage | V_{TH} | $I_D = -1.0 \text{ mA}, V_{DS} = -10 \text{ V}$ | -0.4 | -0.75 | -1.1 | V |
| Drain-source ON resistance *1 | $R_{DS(on)}$ | $I_D = -1.0 \text{ A}, V_{GS} = -4.0 \text{ V}$ | | 80 | 120 | m Ω |
| | | $I_D = -1.0 \text{ A}, V_{GS} = -2.5 \text{ V}$ | | 100 | 170 | |
| | | $I_D = -0.5 \text{ A}, V_{GS} = -1.8 \text{ V}$ | | 140 | 230 | |
| Forward transfer admittance *1 | $ Y_{fs} $ | $I_D = -1.0 \text{ A}, V_{DS} = -10 \text{ V}, f = 1 \text{ MHz}$ | 3.0 | | | S |
| Short-circuit input capacitance (Common source) | C_{iss} | $V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$ | | 300 | | pF |
| Short-circuit output capacitance (Common source) | C_{oss} | | | 30 | | pF |
| Reverse transfer capacitance (Common source) | C_{rss} | | | 35 | | pF |
| Turn-on delay time *2 | $t_{d(on)}$ | $V_{DD} = -10 \text{ V}, V_{GS} = 0 \text{ V to } -4 \text{ V}, I_D = -1 \text{ A}$ | | 6 | | ns |
| Rise time *2 | t_r | | | 8 | | ns |
| Turn-off delay time *2 | $t_{d(off)}$ | $V_{DD} = -10 \text{ V}, V_{GS} = -4 \text{ V to } 0 \text{ V}, I_D = -1 \text{ A}$ | | 57 | | ns |
| Fall time *2 | t_f | | | 55 | | ns |

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *1: Pulse measurement

*2: t_{on} , t_{off} measurement circuit

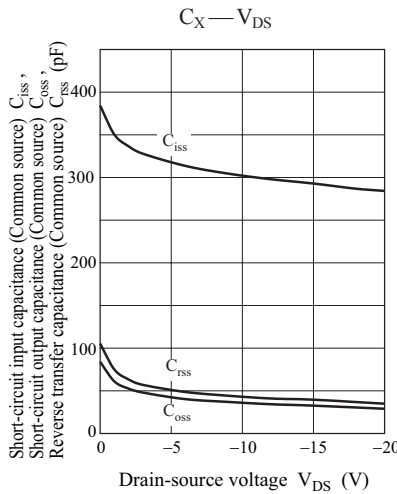
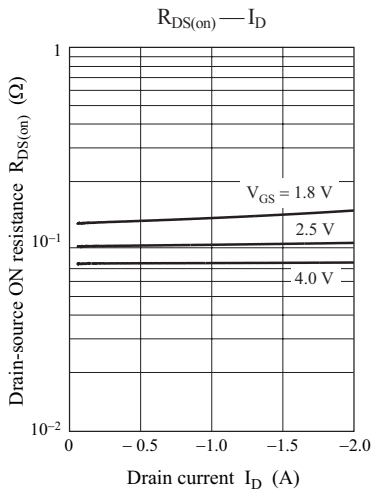
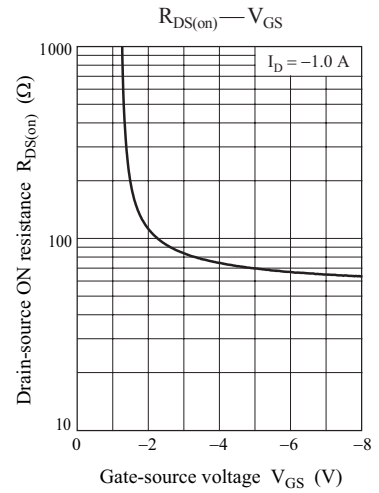
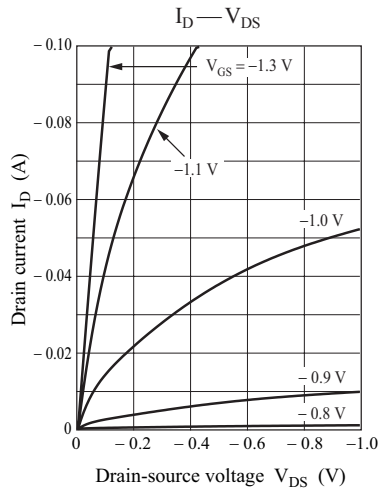
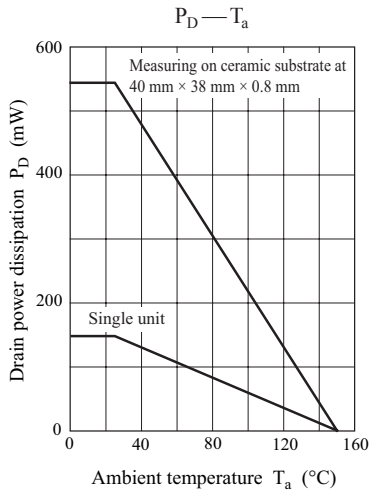


• SBD

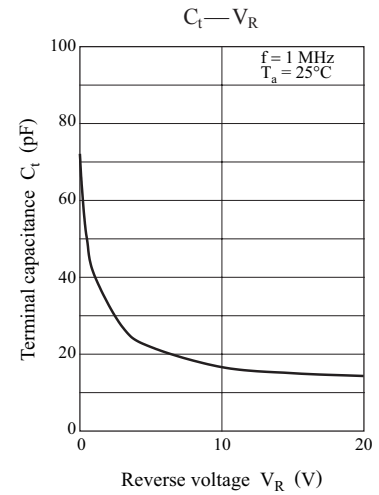
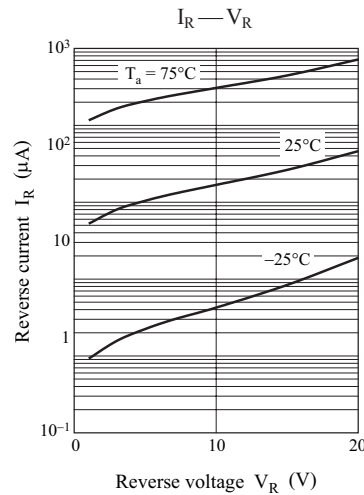
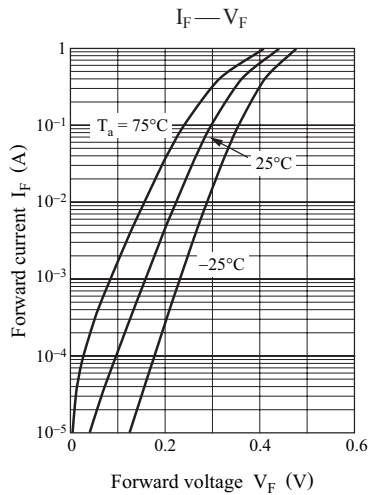
| Parameter | Symbol | Conditions | Min | Typ | Max | Unit |
|-----------------|--------|------------------------|-----|-----|------|---------------|
| Forward voltage | V_F | $I_F = 500 \text{ mA}$ | | | 0.42 | V |
| | | $I_F = 700 \text{ mA}$ | | | 0.45 | V |
| Reverse current | I_R | $V_R = 6 \text{ V}$ | | | 90 | μA |
| | | $V_R = 15 \text{ V}$ | | | 250 | μA |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

Characteristics charts of FET

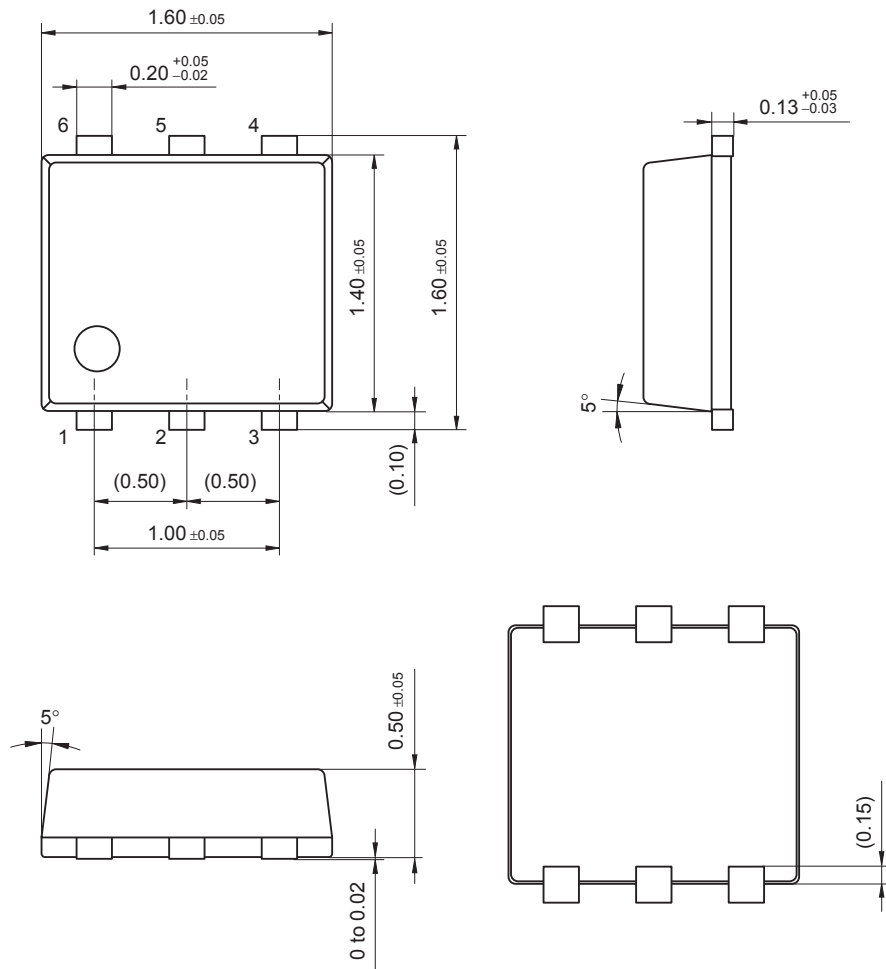


Characteristics charts of SBD



WSSMini6-F1

Unit: mm



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